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8
PATENT NUMBER and
ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10020208	FILING DATE 12/18/2001	CLASS 438	SUBCLASS 201	GAU 2812	EXAMINER AUDVONG
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2818

**CONTINUING DATA VERIFIED:
THIS APPLN CLAIMS BENEFIT OF 60/312,793 08/17/2001

Xeo NC

** FOREIGN APPLICATIONS VERIFIED:

Wink

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed 35 USC 119 conditions met		<input type="checkbox"/> yes <input checked="" type="checkbox"/> no <input type="checkbox"/> yes <input checked="" type="checkbox"/> no	ATTORNEY DOCKET NO 1875.0330001
Verified and Acknowledged Examiners's initials			
TITLE : System and method to screen defect related reliability failures in CMOS SRAMS U.S. DEPT. OF COMM./PAT. & TM-PTG-43SL(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Drawg.	Figs. Drawg.
TERMINAL DISCLAIMER		PREPARED FOR ISSUE	Application Examiner	
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